

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



### Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China







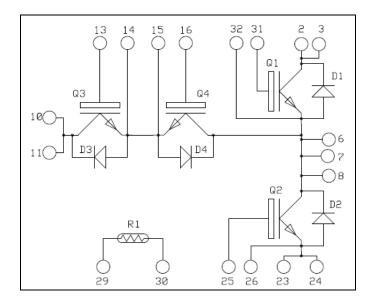


# Phase Leg & Dual Common Emitter Power Module

High speed Trench & Field Stop IGBT4 (Q1, Q2):

 $V_{CES} = 1200V$ ;  $I_C = 80A$  @ Tc = 80°C

Trench & Field Stop IGBT3 (Q3, Q4):



#### Application

• Uninterruptible Power Supplies

#### **Features**

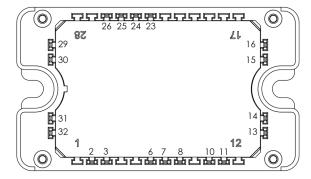
- Q1, Q2 High speed Trench + field Stop IGBT4
  - Low voltage drop
  - Low tail current
- Q3, Q4 Trench + field Stop IGBT3
  - Low voltage drop
  - Low tail current
  - Switching frequency up to 20 kHz

#### • SiC Schottky Diode (D3, D4)

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Kelvin emitter for easy drive
- Very low stray inductance
- High level of integration
- Internal thermistor for temperature monitoring

#### **Benefits**

- Stable temperature behavior
- Very rugged
- Solderable terminals for easy PCB mounting
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Easy paralleling due to positive T<sub>C</sub> of V<sub>CEsat</sub>
- Low profile
- RoHS Compliant



All multiple inputs and outputs must be shorted together 10/11; 23/24; 2/3; ...

All ratings @  $T_j = 25^{\circ}C$  unless otherwise specified

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handing Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



### 1. High speed Trench & Field Stop IGBT4 Phase Leg Q1&Q2 (per IGBT)

### Absolute maximum ratings

Symbol	Parameter		Max ratings	Unit
$V_{CES}$	Collector - Emitter Breakdown Voltage		1200	V
T	Continuous Collector Current	$T_C = 25^{\circ}C$	150	
$I_{C}$	Continuous Conector Current	$T_C = 80$ °C	80	Α
$I_{CM}$	Pulsed Collector Current	$T_C = 25$ °C	320	
$V_{GE}$	Gate – Emitter Voltage		±20	V
$P_{D}$	Maximum Power Dissipation		500	W
RBSOA	Reverse Bias Safe Operating Area	$T_j = 150^{\circ}C$	160A @ 1100V	

### **Electrical Characteristics**

Sym	bol	Characteristic	Test Conditions	Min	Тур	Max	Unit	
$I_{CE}$	ES	Zero Gate Voltage Collector Current	$V_{GE} = 0V$ , $V_{CE} =$			150	μΑ	
V		Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25^{\circ}C$	1.7	2.05	2.4	V
$V_{CE}$	(sat)		$I_C = 80A$	$T_j = 150$ °C		2.6		·
$V_{GE}$	(th)	Gate Threshold Voltage	$V_{GE} = V_{CE}$ , $I_C = 2 \text{ mA}$		5.0	5.8	6.5	V
$I_{GE}$	ES	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE}$	= 0V			240	nA

**Dynamic Characteristics** 

Symbol	Characteristic	Test Condition	ns	Min	Тур	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$			4600		
$C_{oes}$	Output Capacitance	$V_{CE} = 25V$			300		pF
$C_{res}$	Reverse Transfer Capacitance	f = 1MHz			270		
$Q_{G}$	Gate charge	$V_{GE} = 15V, I_{C}$ $V_{CE} = 960V$	= 80A		370		nC
$T_{d(on)}$	Turn-on Delay Time	Inductive Swit	tching (25°C)		30		
$T_{r}$	Rise Time	$V_{GE} = \pm 15V$			57		
$T_{d(off)}$	Turn-off Delay Time	$V_{Bus} = 600V$ $I_{C} = 80A$			290		ns
$T_{\mathrm{f}}$	Fall Time	$R_G = 6\Omega$			16		
$T_{d(on)}$	Turn-on Delay Time		Inductive Switching (150°C)		30		
$T_{r}$	Rise Time	$V_{GE} = \pm 15V$ $V_{Bus} = 600V$			49		ma
$T_{d(off)}$	Turn-off Delay Time	$I_C = 80A$			366		ns
$T_{\mathrm{f}}$	Fall Time	$R_G = 6\Omega$			48		
Eon	Turn on Energy	$V_{GE} = \pm 15V$	$T_i = 25^{\circ}C$		6.4		
Lon	Turn on Energy	$V_{Bus} = 600V$	$T_i = 150^{\circ}C$		7.5		mJ
E	Turn off Energy	$I_C = 80A$	$T_i = 25^{\circ}C$		2.4		1113
$E_{off}$	Turn off Energy	$R_G = 6\Omega$	$T_{i} = 150^{\circ}C$		4.5		
$I_{sc}$	Short Circuit data	$V_{GE} \le 15V ; V_1  t_p \le 10 \mu s ; T_j =$			300		A
$R_{thJC}$	Junction to Case Thermal Resistance		·			0.3	°C/W



### Diode ratings and characteristics (D1 & D2) (per diode)

Symbol	Characteristic	Test Conditions	Test Conditions		Тур	Max	Unit
$V_{RRM}$	Maximum Peak Repetitive Reverse Voltage			1200			V
$I_{RM}$	Maximum Reverse Leakage Current	V <sub>R</sub> =1200V				100	μΑ
$I_F$	DC Forward Current		Tc =80°C		30		A
		$I_F = 30A$			2.6	3.1	
$V_{\mathrm{F}}$	Diode Forward Voltage	$I_F = 60A$			3.2		V
		$I_F = 30A$	$T_j = 125$ °C		1.8		
4	Reverse Recovery Time		$T_j = 25$ °C		300		
$t_{rr}$		$I_F = 30A$ $V_R = 800V$	$T_j = 125$ °C		380		ns
0	Reverse Recovery Charge	$v_R = 800 v$ $di/dt = 200 A/\mu s$	$T_j = 25$ °C		360		C
$Q_{rr}$			$T_{j} = 125^{\circ}C$		1700		пC
$R_{thJC}$	Junction to Case Thermal Resistance					1.2	°C/W

### 2. Trench & Field Stop IGBT3 Dual common emitter Q3&Q4 (per IGBT)

### Absolute maximum ratings

Symbol	Parameter		Max ratings	Unit
$V_{CES}$	Collector - Emitter Breakdown Voltage		600	V
ī	Continuous Collector Current	$T_C = 25^{\circ}C$	100	
$I_{C}$	Continuous Conector Current	$T_C = 80$ °C	75	Α
$I_{CM}$	Pulsed Collector Current	$T_C = 25^{\circ}C$	140	
$V_{GE}$	Gate – Emitter Voltage		±20	V
$P_{D}$	Maximum Power Dissipation	$T_C = 25$ °C	250	W
RBSOA	Reverse Bias Safe Operating Area	$T_{J} = 150^{\circ}C$	150A @ 550V	

#### **Electrical Characteristics**

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit	
$I_{CES}$	Zero Gate Voltage Collector Current	$V_{GE} = 0V, V_{CE} = 600V$				250	μΑ
V	Collector Emitter Saturation Voltage	$V_{GE} = 15V$	$T_j = 25^{\circ}C$		1.5	1.9	V
$V_{CE(sat)}$		$I_C = 75A$	$T_{j} = 150^{\circ}C$		1.7		·
$V_{GE(th)}$	Gate Threshold Voltage	$V_{GE} = V_{CE}, I_C = 600 \mu A$		5.0	5.8	6.5	V
$I_{GES}$	Gate – Emitter Leakage Current	$V_{GE} = 20V, V_{CE}$	= 0V			600	nA



**Dynamic Characteristics** 

Symbol	Characteristic	Test Conditions		Min	Typ	Max	Unit
Cies	Input Capacitance	$V_{GE} = 0V$			4620		
Coes	Output Capacitance	$V_{CE} = 25V$			300		pF
Cres	Reverse Transfer Capacitance	f = 1MHz			140		
$Q_{G}$	Gate charge	$V_{GE}=\pm 15V, I_{C}=7$ $V_{CE}=300V$	75A		0.8		μС
$T_{d(on)}$	Turn-on Delay Time	Inductive Switch	ning (25°C)		110		
$T_{r}$	Rise Time	$V_{GE} = \pm 15V$			45		
$T_{d(off)}$	Turn-off Delay Time	$V_{Bus} = 300V$ $I_{C} = 75A$			200		ns
$T_{\rm f}$	Fall Time	$R_{\rm G} = 4.7\Omega$			40		
$T_{d(on)}$	Turn-on Delay Time	Inductive Switch $V_{GE} = \pm 15V$	ning (150°C)		120		
$T_{\rm r}$	Rise Time	$V_{\text{Bus}} = 300 \text{V}$			50		ns
$T_{d(off)}$	Turn-off Delay Time	$I_C = 75A$			250		
$T_{\rm f}$	Fall Time	$R_G = 4.7\Omega$			60		
Eon	Turn-on Switching Energy	$V_{GE} = \pm 15V$	$T_j = 25^{\circ}C$		0.21		mJ
		$V_{\text{Bus}} = 300V$ $I_{\text{C}} = 75A$	$T_{j} = 150^{\circ}C$ $T_{j} = 25^{\circ}C$		0.36		
$E_{off}$	Turn-off Switching Energy	$R_G = 4.7\Omega$	$T_i = 150$ °C		2.6		mJ
$I_{sc}$	Short Circuit data	$V_{GE} \le 15V ; V_{Bus} = 360V$ $t_p \le 6\mu s ; T_i = 150^{\circ}C$			380		A
$R_{thJC}$	Junction to Case Thermal Resistance					0.60	°C/W

SiC diode ratings and characteristics (D3 & D4) (per diode)

Symbol Characteristic Test Conditions

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit	
$V_{RRM}$	Maximum Peak Repetitive Reverse Voltage			600			V
$I_{RM}$	Maximum Reverse Leakage Current	V <sub>R</sub> =600V	$T_j = 25^{\circ}C$		30	180	μA
$I_{\mathrm{F}}$	DC Forward Current		$T_j = 175^{\circ}C$ $T_c = 100^{\circ}C$		60 30	900	A
$V_{\mathrm{F}}$	Diode Forward Voltage	$I_F = 30A$	$T_i = 25^{\circ}C$ $T_i = 175^{\circ}C$		1.6	1.8 2.4	V
Qc	Total Capacitive Charge	$I_F = 30A$ , $V_R = 600V$ di/dt = $1000A/\mu s$			84		nC
С	$f = 1 \text{MHz}, V_R = 200 \text{V}$		200V		195		рF
	Total Capacitance	$f = 1MHz, V_R =$	400V		150		pr.
$R_{thJC}$	Junction to Case Thermal Resistance					1	°C/W



### 3. Thermal & Package characteristics

Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

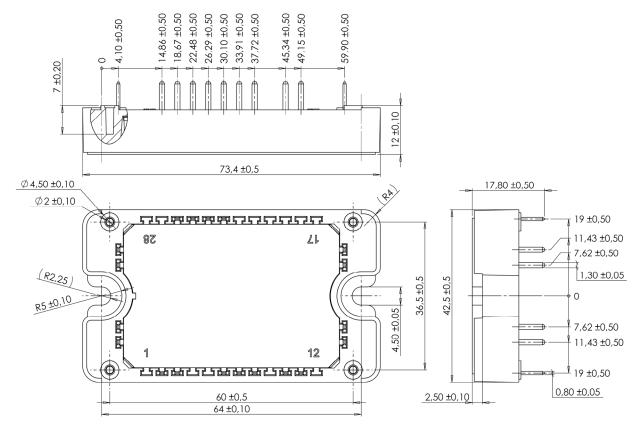
Symbol	Characteristic	Min	Тур	Max	Unit
R <sub>25</sub>	Resistance @ 25°C		22		kΩ
$\Delta R_{25}/R_{25}$				5	%
$B_{25/100}$	$T_{25} = 298.15 \text{ K}$		3980		K
$\Delta B/B$				3	%

$$R_{T} = \frac{R_{25}}{\exp \left[ B_{25/85} \left( \frac{1}{T_{25}} - \frac{1}{T} \right) \right]} \quad \text{T: Thermistor temperature}$$
 
$$R_{T}: \text{ Thermistor value at T}$$

### Thermal and package characteristics

Symbol	Characteristic			Min	Тур	Max	Unit
$V_{ISOL}$	RMS Isolation Voltage, any terminal to case t=1 min, 50/60Hz			4000			V
$T_{J}$	Operating junction temperature range			-40		175	
$T_{STG}$	Storage Temperature Range			-40		125	°C
$T_{\rm C}$	Operating Case Temperature					100	
Torque	Mounting torque	To heatsink	M4	2		3	N.m
Wt	Package Weight		·			110	g

### **SP3F Package outline** (dimensions in mm)

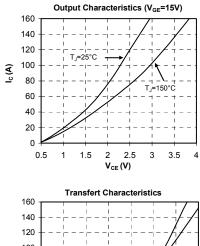


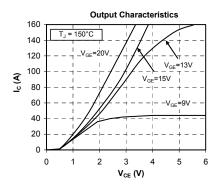
See application note 1906 - Mounting Instructions for SP3F Power Modules on www.microsemi.com

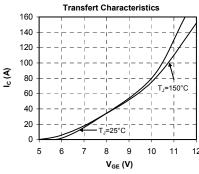


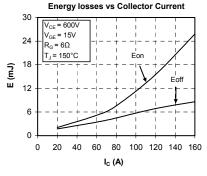
#### 4. Typical performance curve

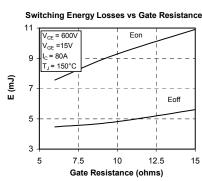
### Q1, Q2 High speed Trench + field stop IGBT4 + CR1 & CR2 diode characteristics

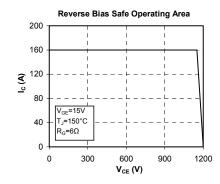


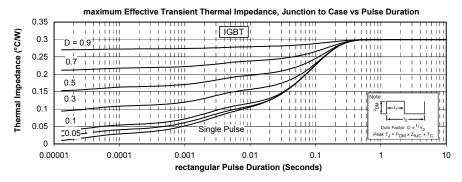




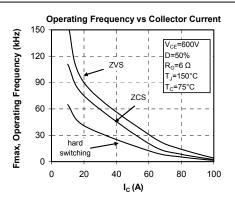


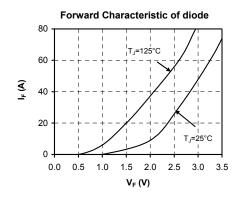


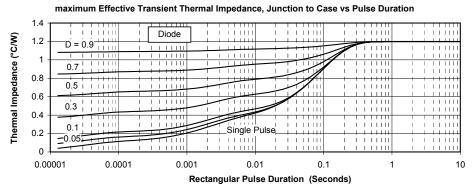




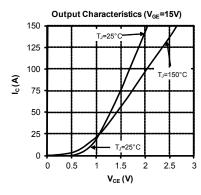


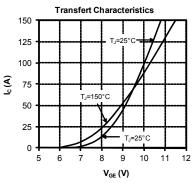


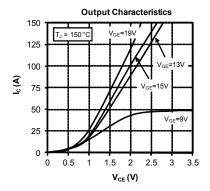


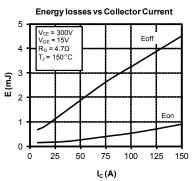


### Q3, Q4 Trench + field stop IGBT3

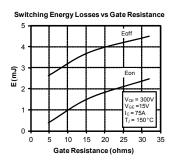


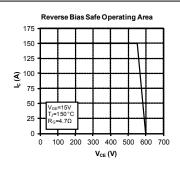


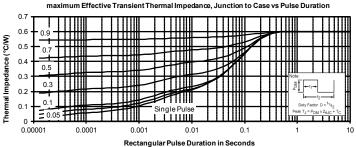




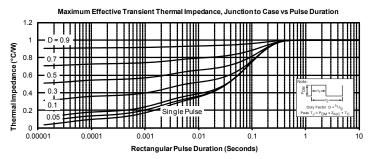


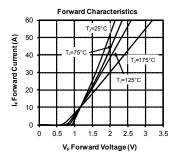


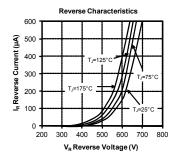


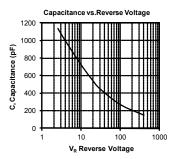


#### CR3 & CR4 SiC diode characteristics











#### **DISCLAIMER**

The information contained in the document (unless it is publicly available on the Web without access restrictions) is PROPRIETARY AND CONFIDENTIAL information of Microsemi and cannot be copied, published, uploaded, posted, transmitted, distributed or disclosed or used without the express duly signed written consent of Microsemi. If the recipient of this document has entered into a disclosure agreement with Microsemi, then the terms of such Agreement will also apply. This document and the information contained herein may not be modified, by any person other than authorized personnel of Microsemi. No license under any patent, copyright, trade secret or other intellectual property right is granted to or conferred upon you by disclosure or delivery of the information, either expressly, by implication, inducement, estoppels or otherwise. Any license under such intellectual property rights must be approved by Microsemi in writing signed by an officer of Microsemi.

Microsemi reserves the right to change the configuration, functionality and performance of its products at anytime without any notice. This product has been subject to limited testing and should not be used in conjunction with life-support or other mission-critical equipment or applications. Microsemi assumes no liability whatsoever, and Microsemi disclaims any express or implied warranty, relating to sale and/or use of Microsemi products including liability or warranties relating to fitness for a particular purpose, merchantability, or infringement of any patent, copyright or other intellectual property right. Any performance specifications believed to be reliable but are not verified and customer or user must conduct and complete all performance and other testing of this product as well as any user or customers final application. User or customer shall not rely on any data and performance specifications or parameters provided by Microsemi. It is the customer's and user's responsibility to independently determine suitability of any Microsemi product and to test and verify the same. The information contained herein is provided "AS IS, WHERE IS" and with all faults, and the entire risk associated with such information is entirely with the User. Microsemi specifically disclaims any liability of any kind including for consequential, incidental and punitive damages as well as lost profit. The product is subject to other terms and conditions which can be located on the web at http://www.microsemi.com/legal/tnc.asp

#### Life Support Application

Seller's Products are not designed, intended, or authorized for use as components in systems intended for space, aviation, surgical implant into the body, in other applications intended to support or sustain life, or for any other application in which the failure of the Seller's Product could create a situation where personal injury, death or property damage or loss may occur (collectively "Life Support Applications").

Buyer agrees not to use Products in any Life Support Applications and to the extent it does it shall conduct extensive testing of the Product in such applications and further agrees to indemnify and hold Seller, and its officers, employees, subsidiaries, affiliates, agents, sales representatives and distributors harmless against all claims, costs, damages and expenses, and attorneys' fees and costs arising, directly or directly, out of any claims of personal injury, death, damage or otherwise associated with the use of the goods in Life Support Applications, even if such claim includes allegations that Seller was negligent regarding the design or manufacture of the goods.

Buyer must notify Seller in writing before using Seller's Products in Life Support Applications. Seller will study with Buyer alternative solutions to meet Buyer application specification based on Sellers sales conditions applicable for the new proposed specific part.